

Fig.1

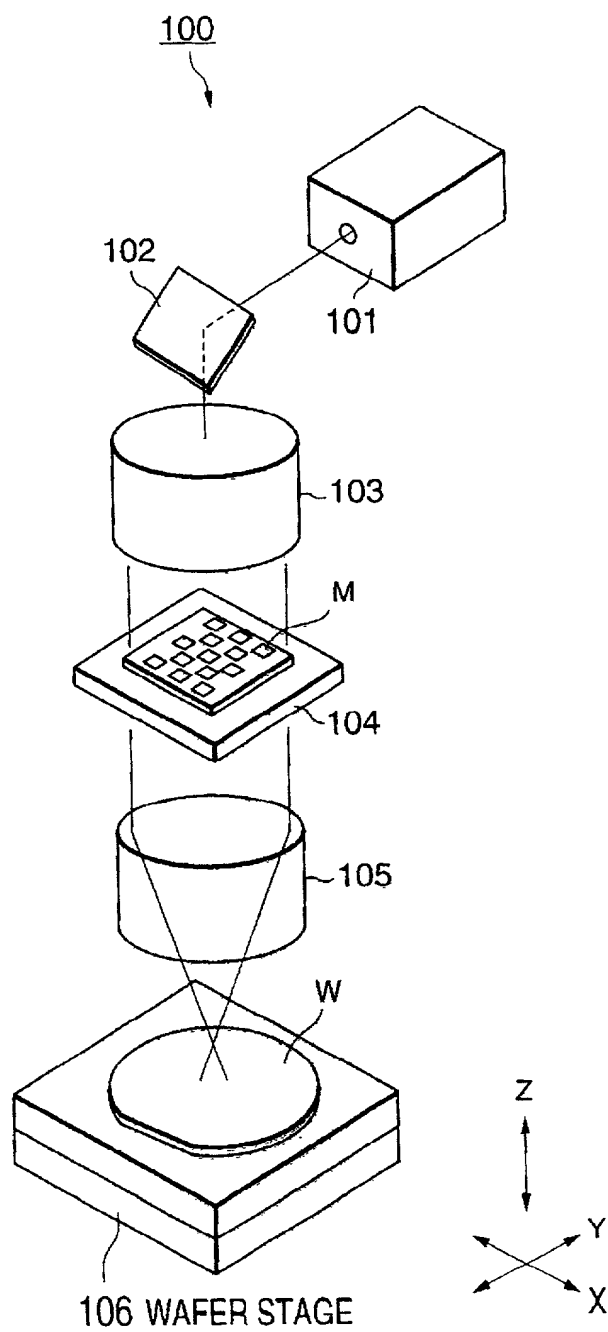


Fig.2

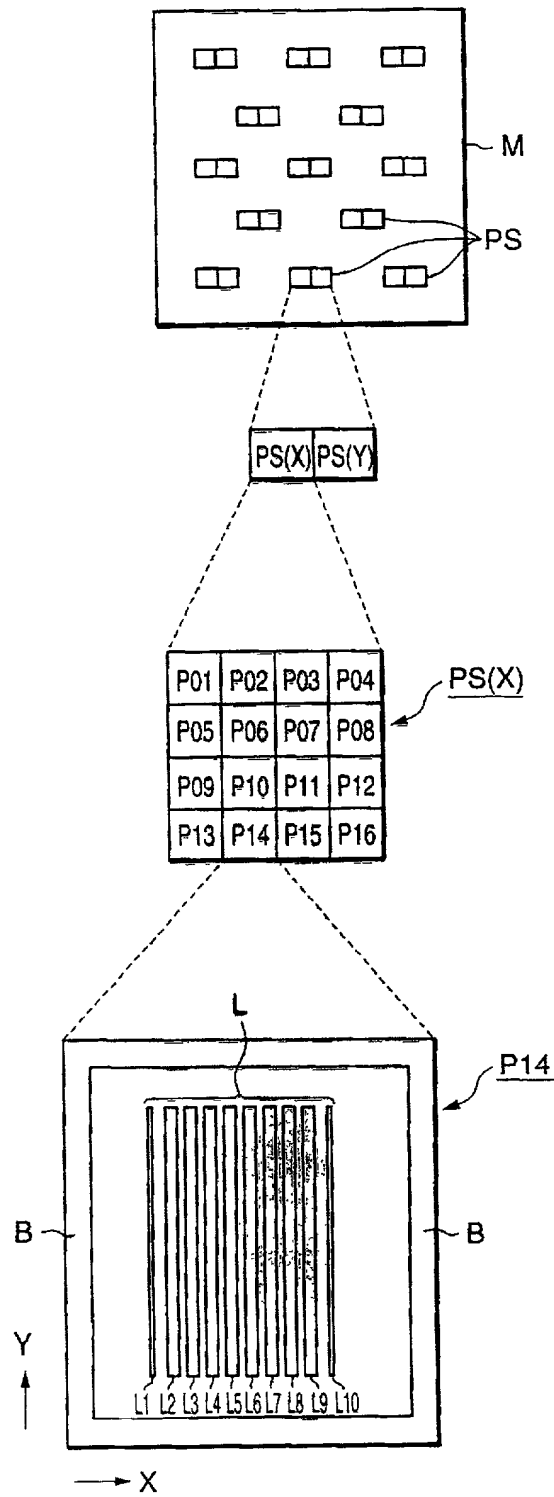


Fig.3(a)

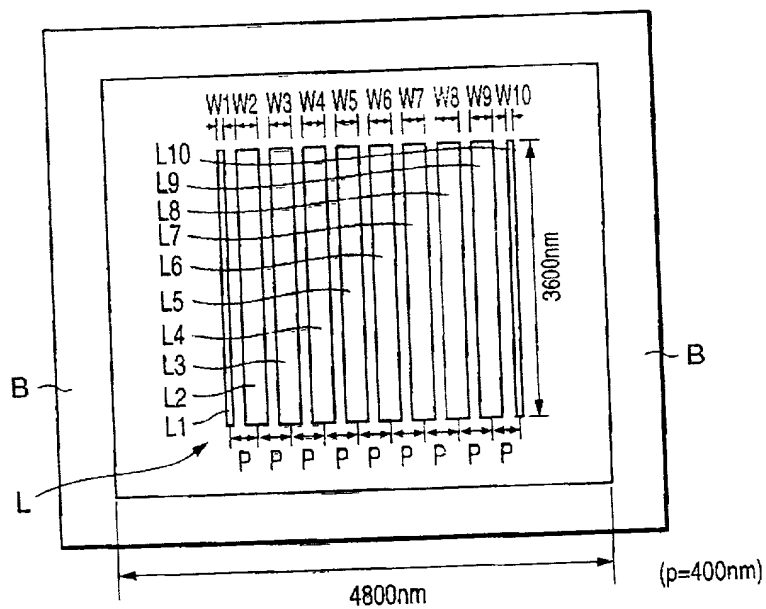
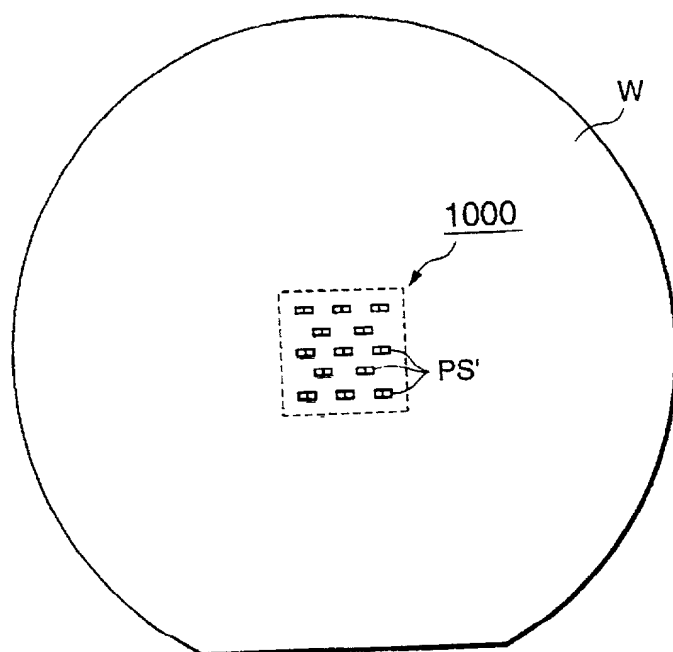


Fig.3(b)

		P02	P03	P04	
	W1,W10 =200nm	" =195nm	" =190nm	" =185nm	
P06	" =180nm	" =175nm	" =170nm	" =165nm	P07
P05					P08
P10	" =160nm	" =155nm	" =150nm	" =145nm	P11
P09					P12
P13	" =140nm	" =135nm	" =130nm	" =125nm	P16
		P14	P15		

Fig.4



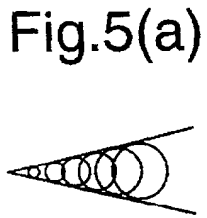


Fig.5(b)

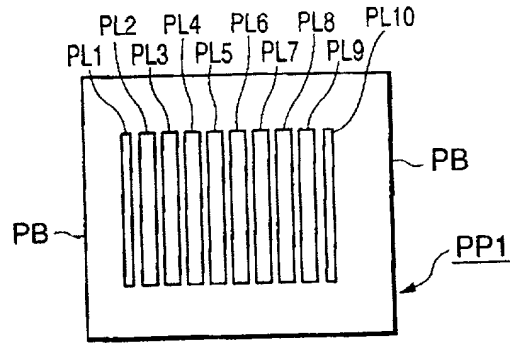


Fig.5(c)

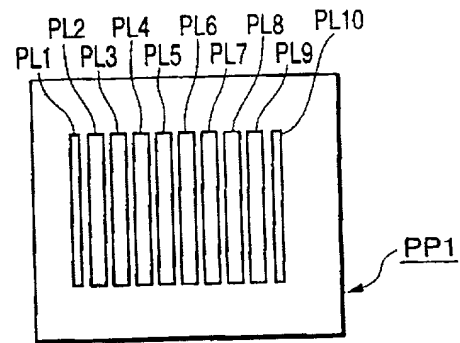


Fig.5(d)

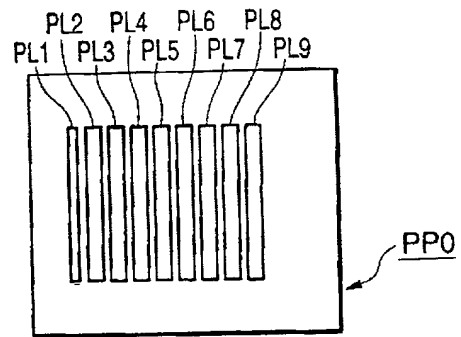


Fig.5(e)

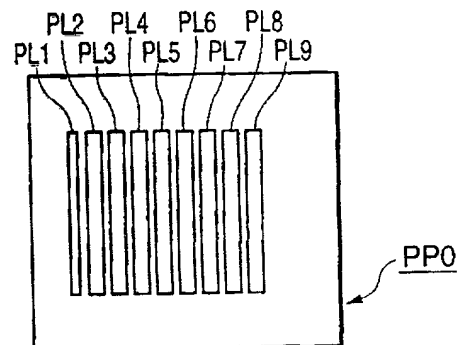


Fig.6(b)

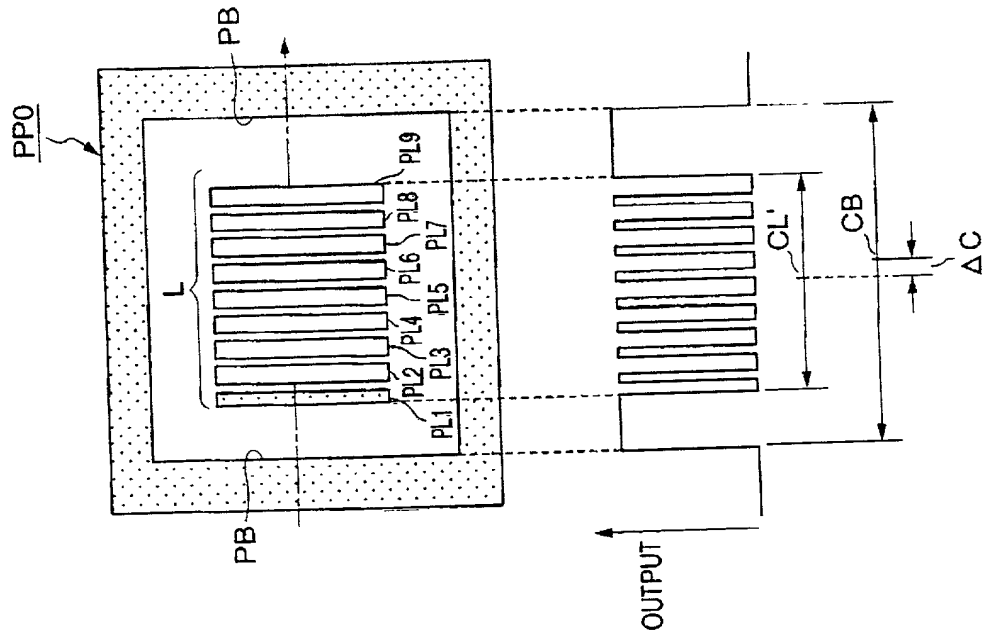


Fig.6(a)

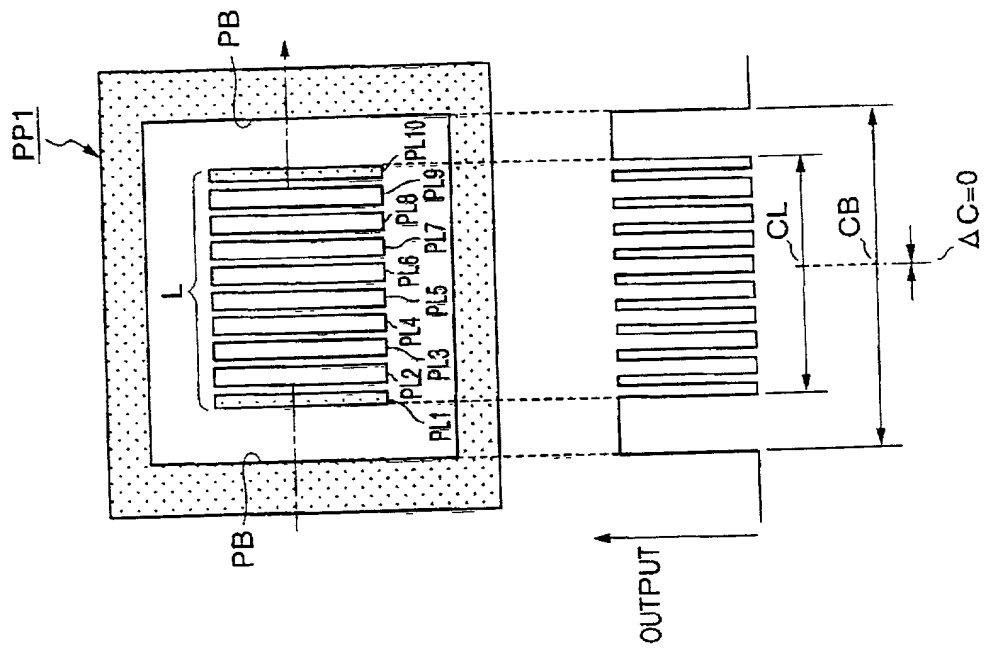


Fig.7

RELATIVE POSITIONAL DEVIATION  
(RESULT OF OVERLAY MEASUREMENT)

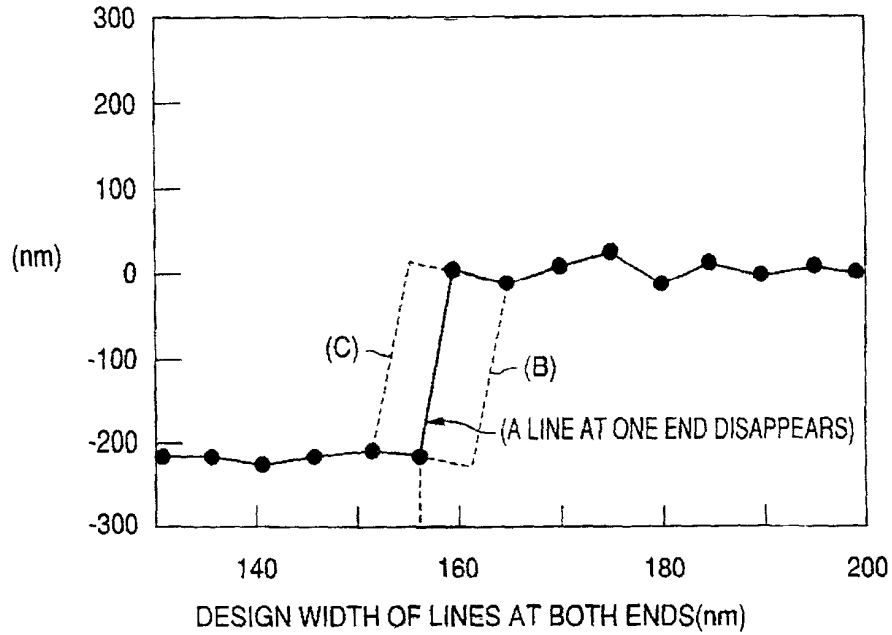


Fig.8

LINE WIDTH RELATED TO A MISSING  
LINE PATTERN AT ONE END

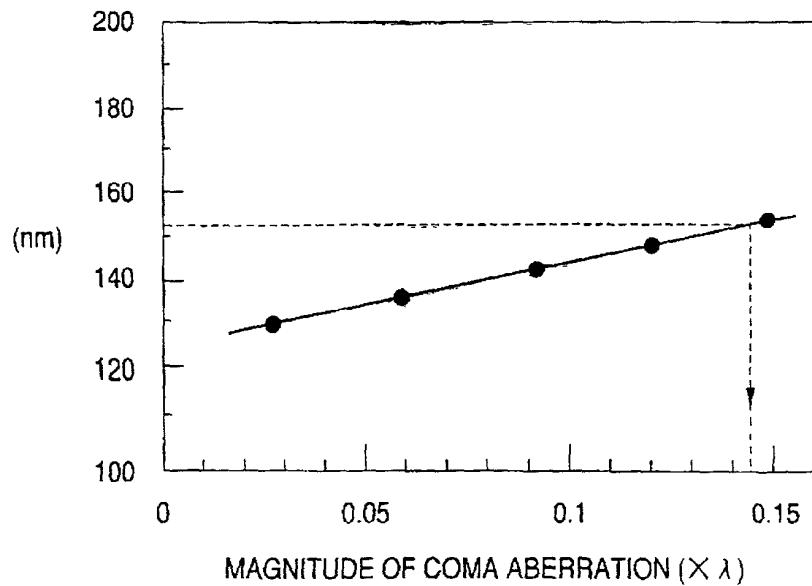


Fig.9

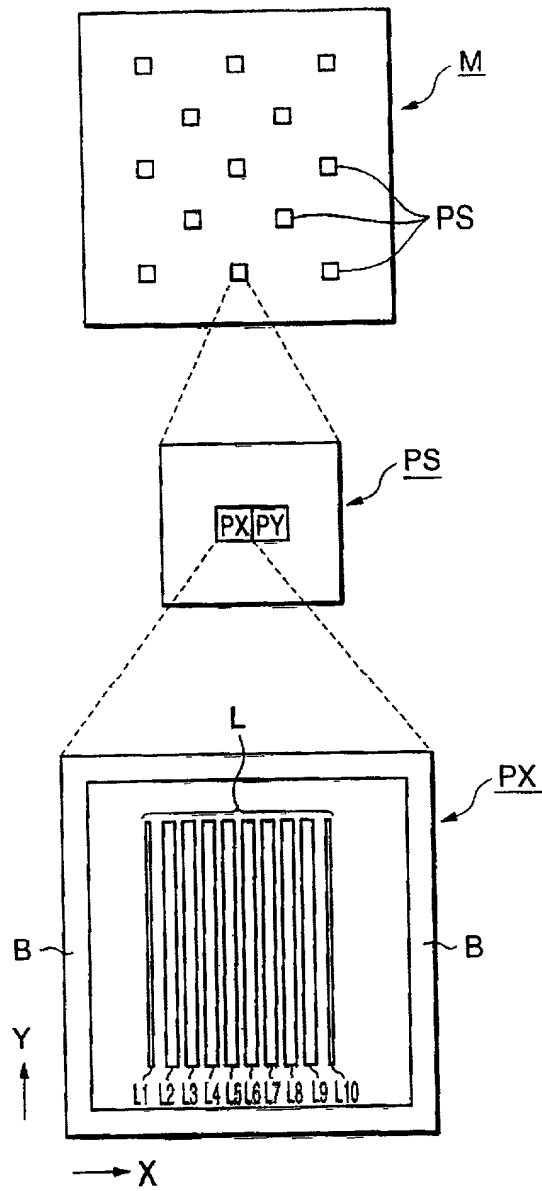




Fig.10(a)

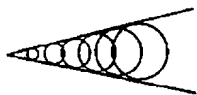


Fig.10(b)

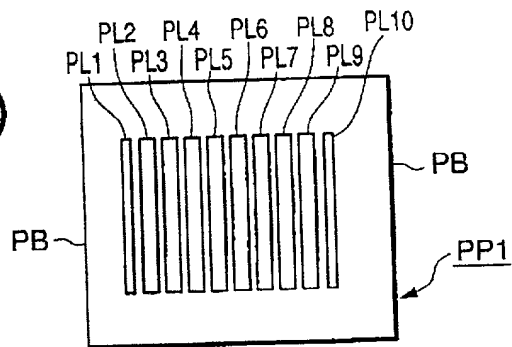


Fig.10(c)

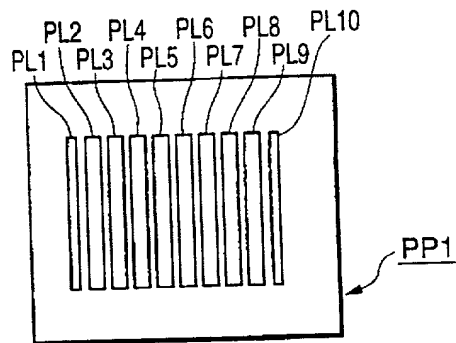


Fig.10(d)

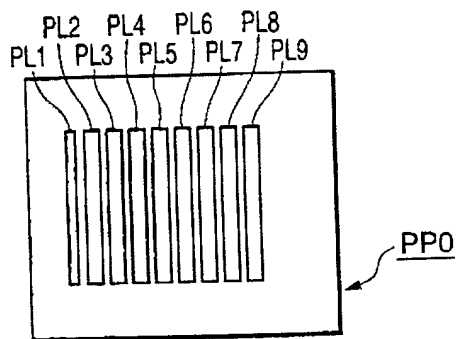


Fig.10(e)

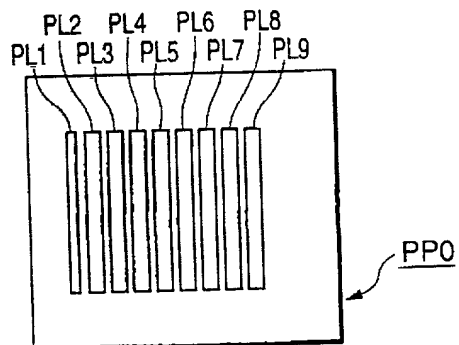


Fig.11

RELATIVE POSITIONAL DEVIATION  
(RESULT OF OVERLAY MEASUREMENT)

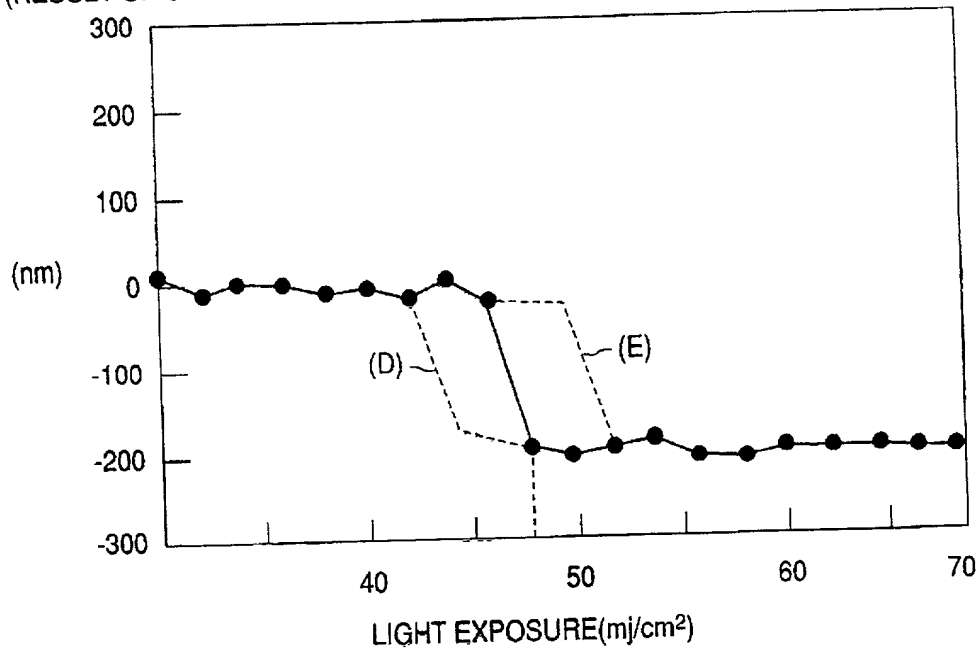


Fig.12

RIGHT EXPOSURE RELATED TO A MISSING  
LINE PATTERN AT ONE END

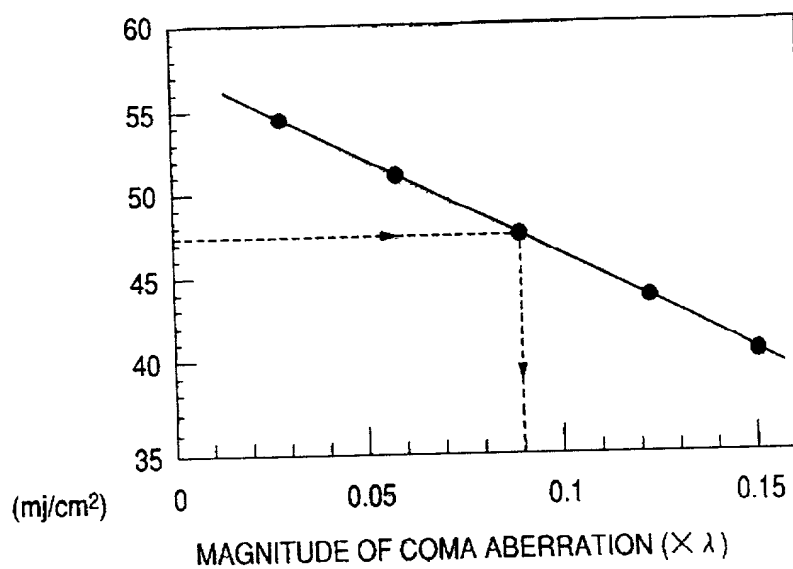


Fig.13(a)

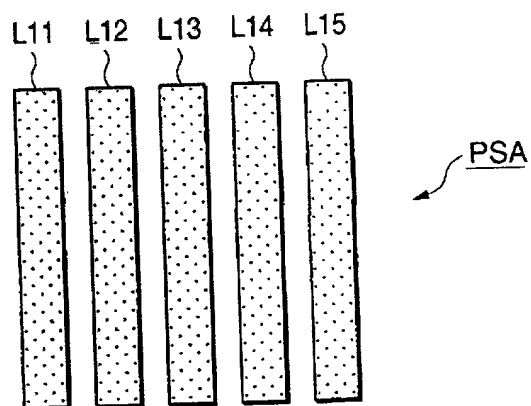


Fig.13(b)

